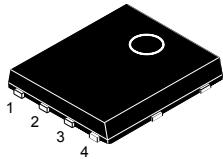
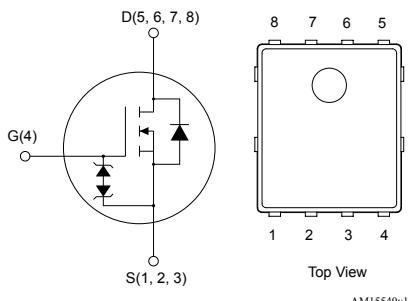


**N-channel 600 V, 220 mΩ typ., 10 A, MDmesh™ M6 Power MOSFET  
in a PowerFLAT™ 5x6 HV package**

## Features


**PowerFLAT™ 5x6 HV**


## Applications

- Reduced switching losses
- Lower  $R_{DS(on)}$  per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

## Description

The new MDmesh™ M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent  $R_{DS(on)}$  per area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.



### Product status link

[STL22N60M6](#)

### Product summary

<b>Order code</b>	STL22N60M6
<b>Marking</b>	22N60M6
<b>Package</b>	PowerFLAT™ 5x6 HV
<b>Packing</b>	Tape and reel

## 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_{case} = 25^\circ\text{C}$	10	A
	Drain current (continuous) at $T_{case} = 100^\circ\text{C}$	6	
$I_{DM}^{(1)}$	Drain current (pulsed)	40	A
$P_{TOT}$	Total power dissipation at $T_{case} = 25^\circ\text{C}$	57	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
	MOSFET $dv/dt$ ruggedness	100	
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ\text{C}$
$T_j$	Operating junction temperature range		

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 10 \text{ A}$ ,  $di/dt = 400 \text{ A}/\mu\text{s}$ ,  $V_{DS} < V_{(BR)DSS}$ ,  $V_{DD} = 400 \text{ V}$
3.  $V_{DS} \leq 480 \text{ V}$

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	2.2	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	50	$^\circ\text{C}/\text{W}$

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board.

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_{Jmax}$ )	2.9	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	230	mJ

## 2 Electrical characteristics

( $T_{case} = 25^\circ\text{C}$  unless otherwise specified).

**Table 4. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_{case} = 125^\circ\text{C}^{(1)}$			100	
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 5$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3.25	4	4.75	V
$R_{DS(on)}$	Static drain-source on-resistance	$I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$		220	250	$\text{m}\Omega$

1. Defined by design, not subject to production test.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	800	-	$\text{pF}$
$C_{oss}$	Output capacitance		-	52.6	-	
$C_{rss}$	Reverse transfer capacitance		-	4.3	-	
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	181	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	4.7	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 15 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	20	-	$\text{nC}$
$Q_{gs}$	Gate-source charge		-	5.6	-	
$Q_{gd}$	Gate-drain charge		-	9.5	-	

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 7.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	13.6	-	ns
$t_r$	Rise time		-	6.3	-	
$t_{d(off)}$	Turn-off delay time		-	32	-	
$t_f$	Fall time		-	8.7	-	

**Table 7. Source-drain diode**

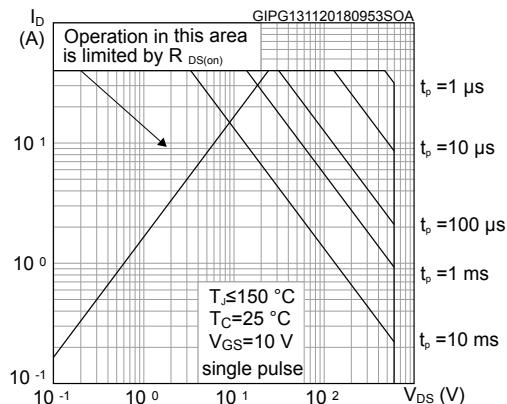
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		10	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		40	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 10 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 15 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}$	-	217		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	1.99		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	18.3		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 15 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}, T_j = 150^\circ\text{C}$	-	299		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	2.95		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	19.7		A

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

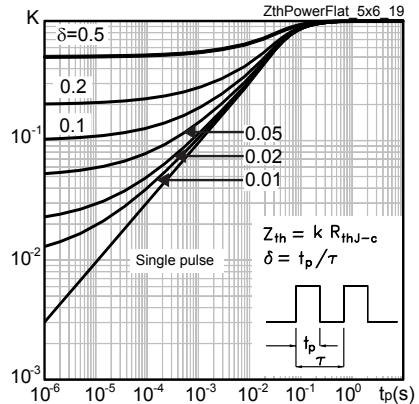
## 2.1

### Electrical characteristics (curves)

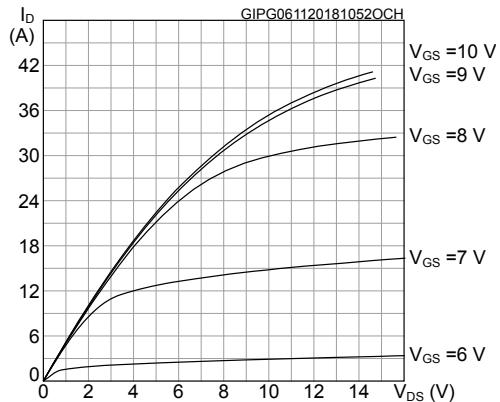
**Figure 1. Safe operating area**



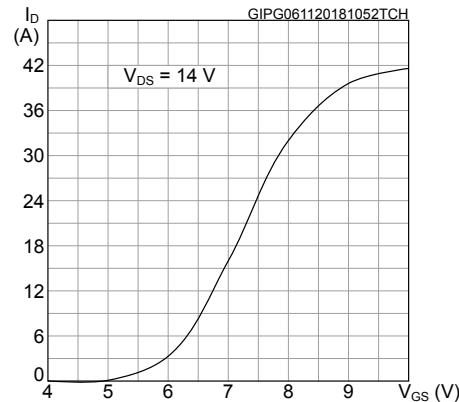
**Figure 2. Thermal impedance**



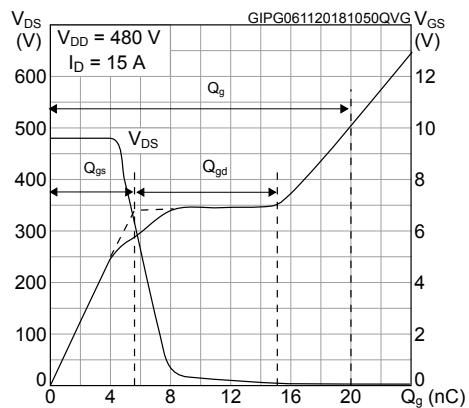
**Figure 3. Output characteristics**



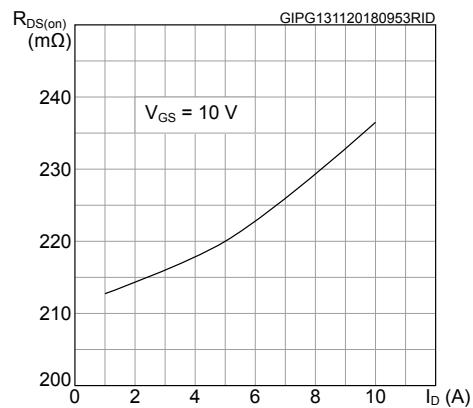
**Figure 4. Transfer characteristics**

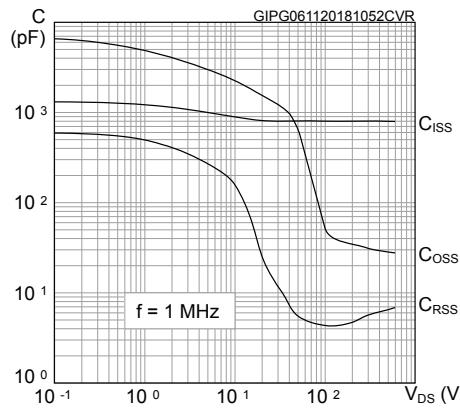
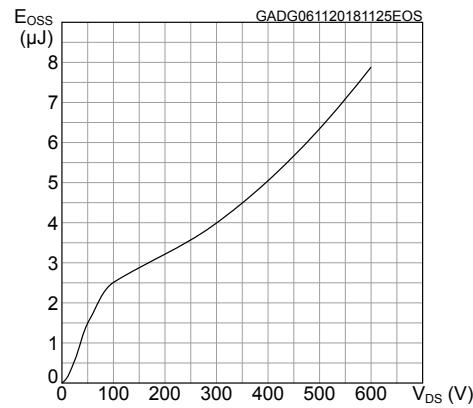
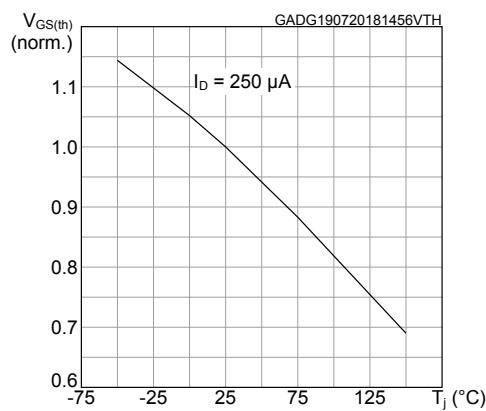
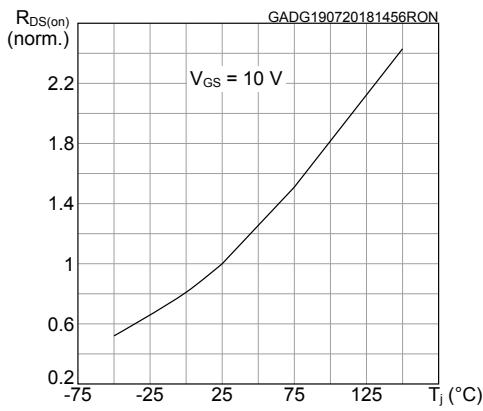
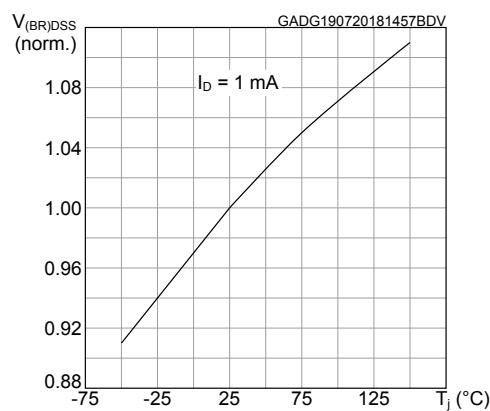
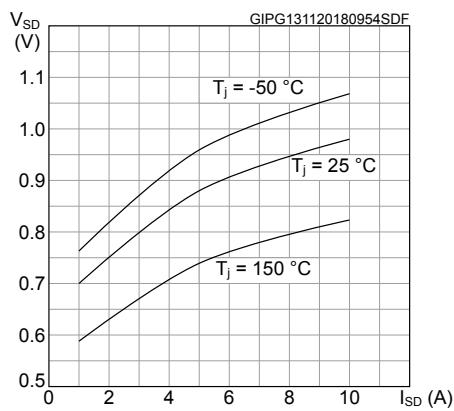


**Figure 5. Gate charge vs gate-source voltage**



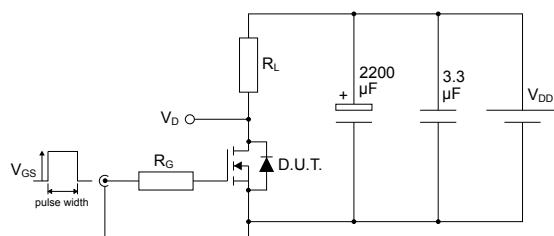
**Figure 6. Static drain-source on-resistance**



**Figure 7. Capacitance variations**

**Figure 8. Output capacitance stored energy**

**Figure 9. Normalized gate threshold voltage vs temperature**

**Figure 10. Normalized on-resistance vs temperature**

**Figure 11. Normalized V\_(BR)DSS vs temperature**

**Figure 12. Source-drain diode forward characteristics**


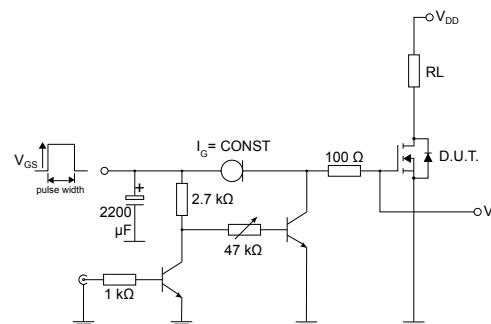
### 3 Test circuits

**Figure 13.** Test circuit for resistive load switching times



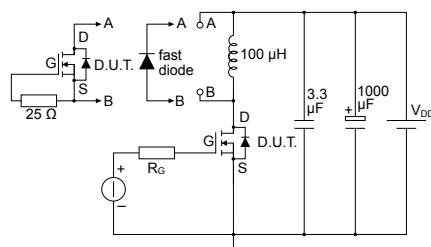
AM01468v1

**Figure 14.** Test circuit for gate charge behavior



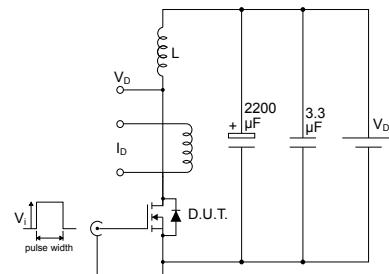
AM01469v10

**Figure 15.** Test circuit for inductive load switching and diode recovery times



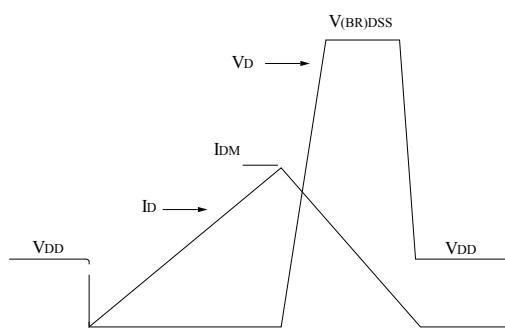
AM01470v1

**Figure 16.** Unclamped inductive load test circuit



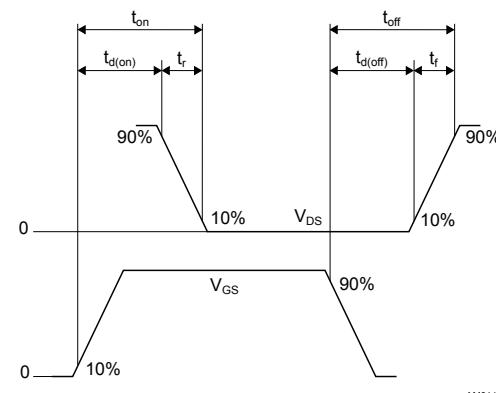
AM01471v1

**Figure 17.** Unclamped inductive waveform



AM01472v1

**Figure 18.** Switching time waveform



AM01473v1

**4**

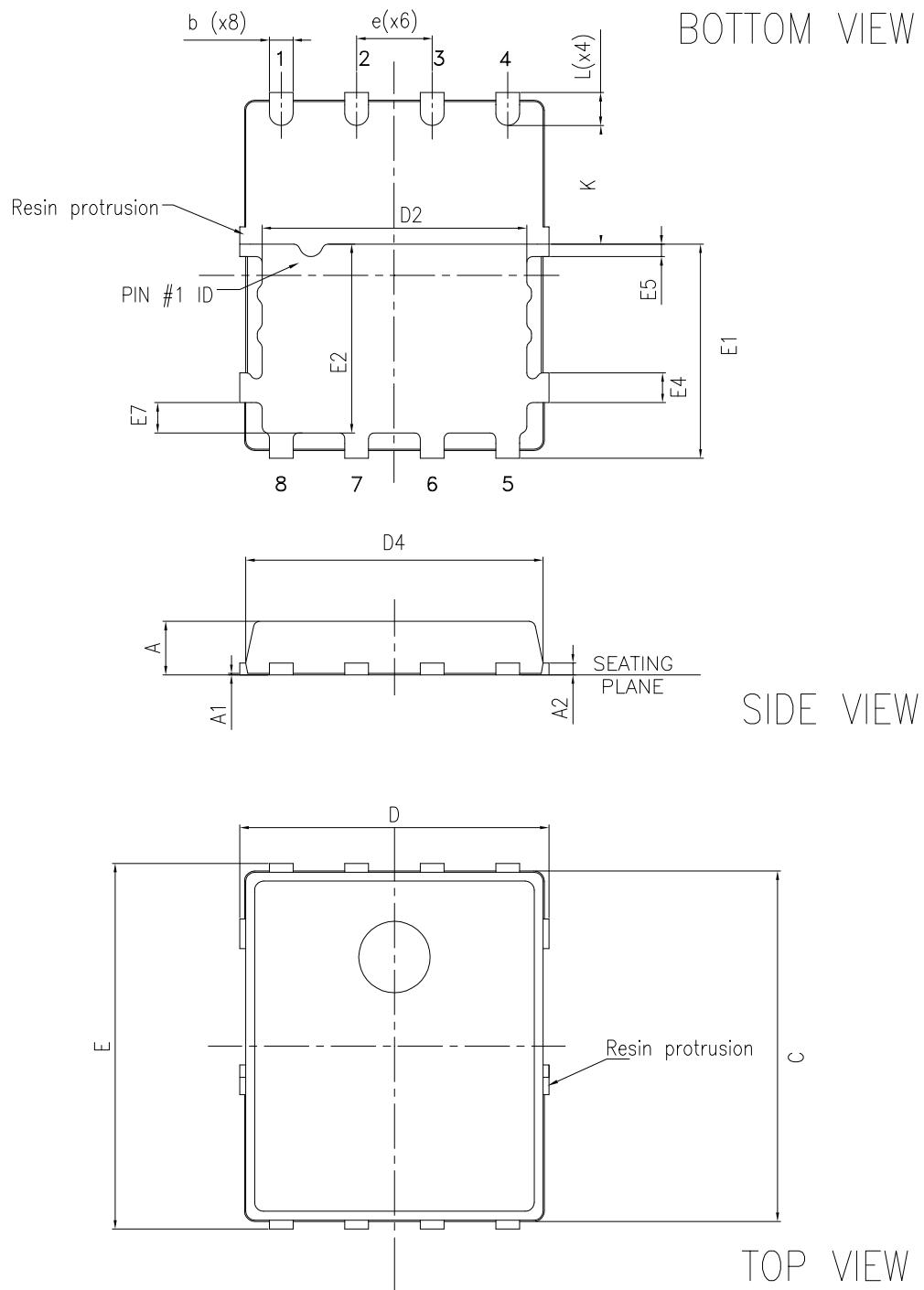
## Package information

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In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

## 4.1 PowerFLAT™ 5x6 HV package information

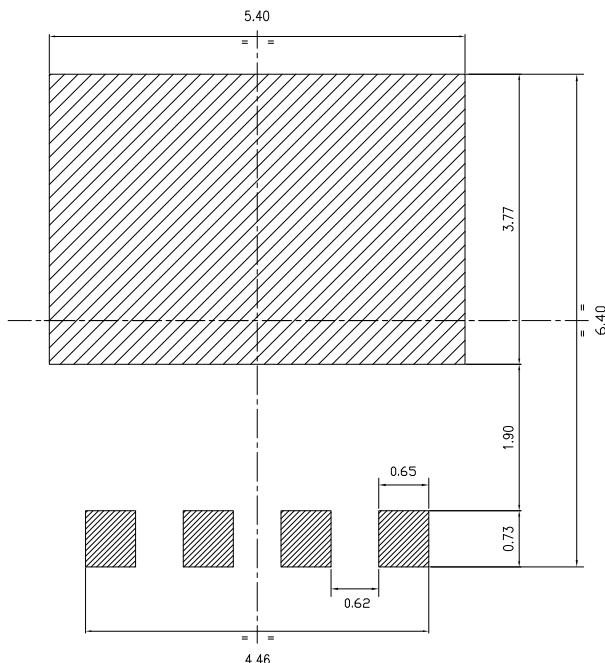
Figure 19. PowerFLAT™ 5x6 HV package outline



8368143\_Rev\_4

**Table 8.** PowerFLAT™ 5x6 HV mechanical data

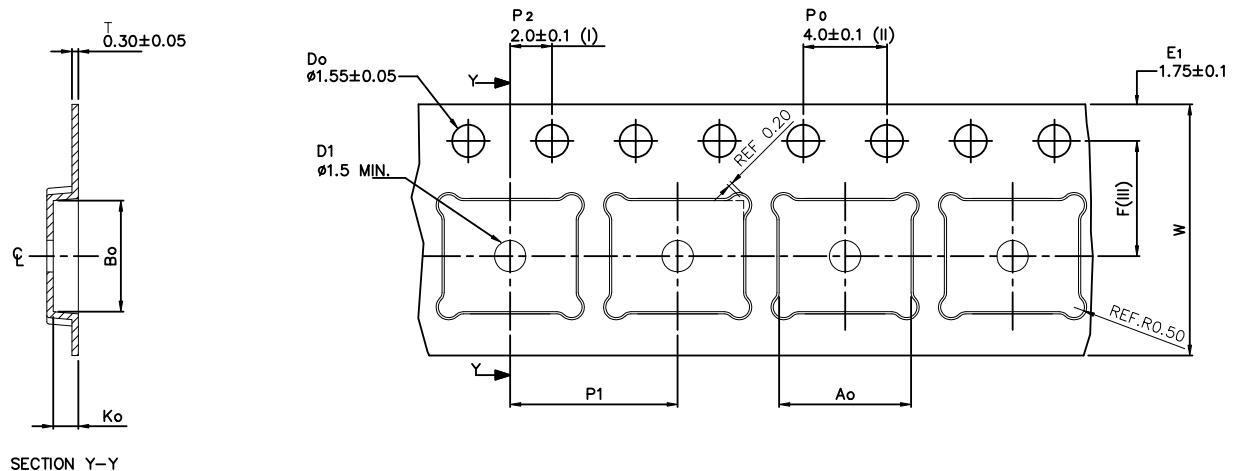
Dim.	mm		
	Min.	Typ.	Max.
A	0.80		1.00
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
C	5.60	5.80	6.00
D	5.10	5.20	5.30
D2	4.30	4.40	4.50
D4	4.60	4.80	5.00
E	6.05	6.15	6.25
E1	3.50	3.60	3.70
E2	3.10	3.20	3.30
E4	0.40	0.50	0.60
E5	0.10	0.20	0.30
E7	0.40	0.50	0.60
e		1.27	
L	0.50	0.55	0.60
K	1.90	2.00	2.10

**Figure 20.** PowerFLAT™ 5x6 HV recommended footprint (dimensions are in mm)

8368143\_Rev\_4\_footprint

## 4.2 PowerFLAT™ 5x6 packing information

**Figure 21.** PowerFLAT™ 5x6 tape (dimensions are in mm)



SECTION Y-Y

A <sub>0</sub>	6.30 +/− 0.1
B <sub>0</sub>	5.30 +/− 0.1
K <sub>o</sub>	1.20 +/− 0.1
F	5.50 +/− 0.1
P <sub>1</sub>	8.00 +/− 0.1
W	12.00 +/− 0.3

(I) Measured from centreline of sprocket hole to centreline of pocket.

Base and bulk quantity 3000 pcs  
All dimensions are in millimeters

(II) Cumulative tolerance of 10 sprocket holes is ±0.20.

(III) Measured from centreline of sprocket hole to centreline of pocket

8234350\_Tape\_rev\_C

**Figure 22.** PowerFLAT™ 5x6 package orientation in carrier tape

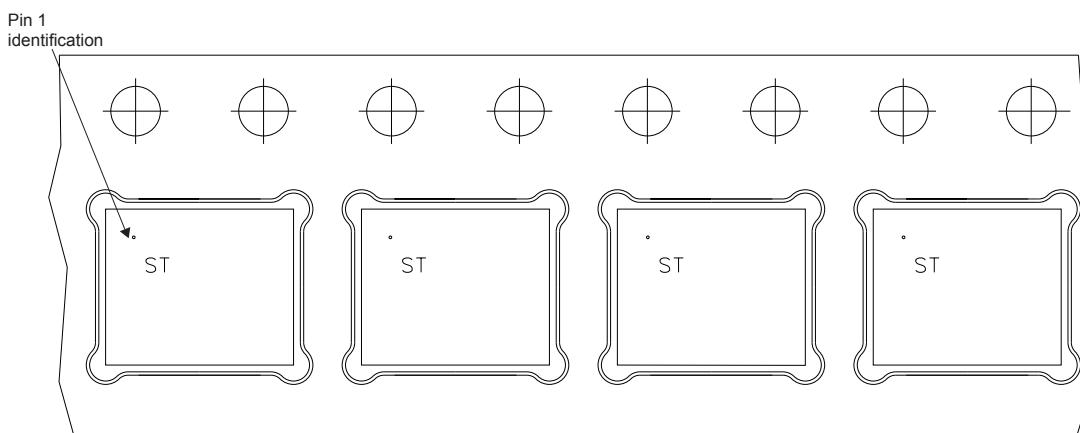
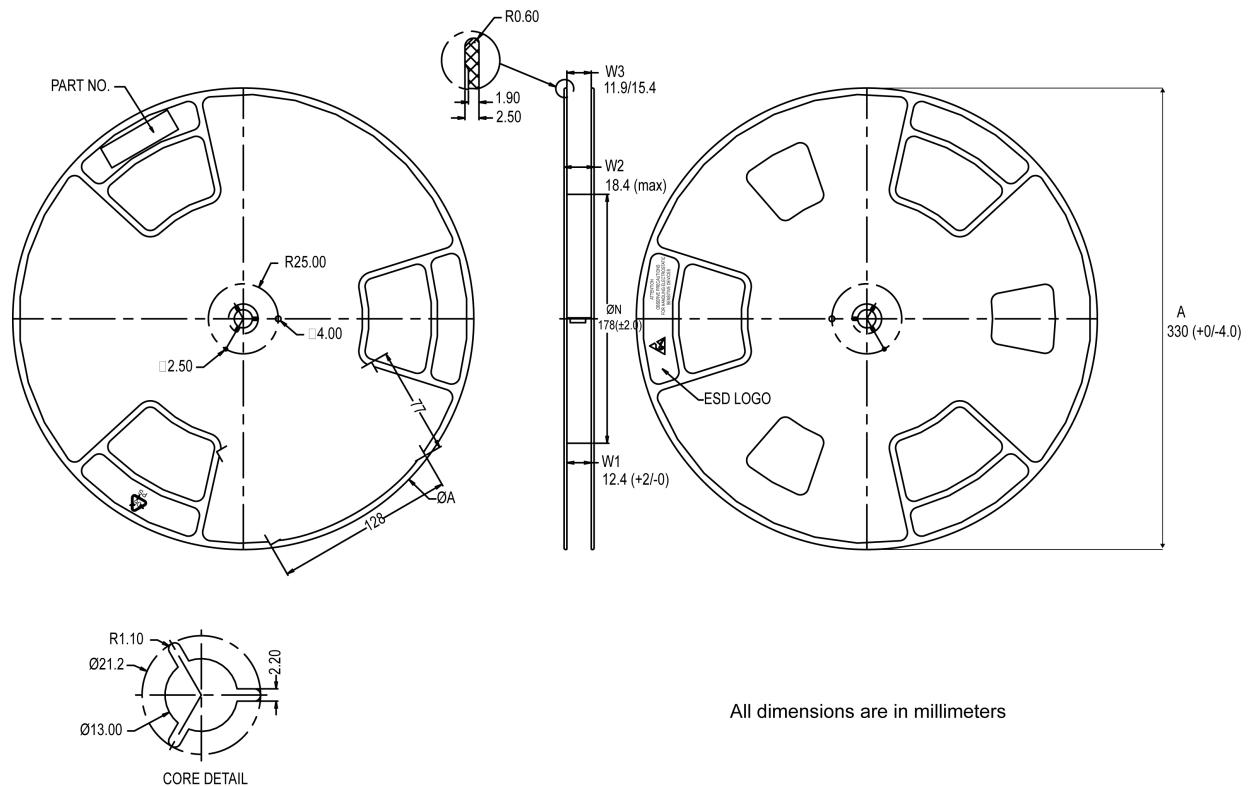


Figure 23. PowerFLAT™ 5x6 reel



8234350\_Reel\_rev\_C

## Revision history

**Table 9. Document revision history**

Date	Version	Changes
16-Nov-2018	1	First release.

## Contents

<b>1</b>	<b>Electrical ratings .....</b>	<b>2</b>
<b>2</b>	<b>Electrical characteristics.....</b>	<b>3</b>
<b>2.1</b>	Electrical characteristics (curves) .....	5
<b>3</b>	<b>Test circuits .....</b>	<b>7</b>
<b>4</b>	<b>Package information.....</b>	<b>8</b>
<b>4.1</b>	PowerFLAT™ 5x6 HV package information.....	8
<b>4.2</b>	PowerFLAT™ 5x6 packing information .....	10
	<b>Revision history .....</b>	<b>13</b>

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